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| Notice of References Cited | Application/Control No. 10/534,200 | | Applicant(s)/Patent Under Reexamination MEIYAPPAN, PALANIAPPAN | |
| | Examiner SAYED T. ZEWARDI | | Art Unit 2617 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-5,491,837 | 02-1996 | Haartsen, Jacobus C. | 455/62 |
| * | B | US-6,529,488 | 03-2003 | Urs et al. | 370/330 |
| * | C | US-6,366,195 | 04-2002 | Harel et al. | 340/7.21 |
| * | D | US-6,850,506 | 02-2005 | Holtzman et al. | 370/335 |
| * | E | US-5,726,978 | 03-1998 | Frodigh et al. | 370/252 |
| * | F | US-6,751,444 | 06-2004 | Meiyappan, Palaniappan | 455/69 |
| * | G | US-5,887,245 | 03-1999 | Lindroth et al. | 455/69 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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